

Roll No:

| | | | | | | | | | | | | |
|--|--|--|--|--|--|--|--|--|--|--|--|--|
| | | | | | | | | | | | | |
|--|--|--|--|--|--|--|--|--|--|--|--|--|

NOIDA INSTITUTE OF ENGINEERING AND TECHNOLOGY, GREATER NOIDA

(An Autonomous Institute Affiliated to AKTU, Lucknow)

B. Tech

SEM: IV- THEORY EXAMINATION (2024-2025)

Subject **CMOS Digital Integrated Circuit**

Time: 3:00 Hours

Max. Marks:100

General Instructions:**IMP:** Verify that you have received question paper with correct course, code, branch etc.

1. This Question paper comprises of three Sections -A, B, & C. It consists of Multiple Choice Questions (MCQ's) & Subjective type questions.
2. Maximum marks for each question are indicated on right hand side of each question.
3. Illustrate your answers with neat sketches wherever necessary.
4. Assume suitable data if necessary.
5. Preferably, write the answers in sequential order.
6. No sheet should be left blank. Any written material after a blank sheet will not be evaluated/checked.

SECTION – A

20

1. Attempt all parts:-

- | | | |
|------|---|---|
| 1-a. | Which step is typically the first in the VLSI design flow? (CO1,K2) | 1 |
| | a) Physical design | |
| | b) Logic synthesis | |
| | c) Specification | |
| | d) Floor planning | |
| 1-b. | In CMOS n-Well process, the n-well is used for placing: (CO1,K2) | 1 |
| | a) NMOS only | |
| | b) PMOS only | |
| | c) Both NMOS and PMOS | |
| | d) None of the above | |
| 1-c. | Which of the following defines the noise margin high (NMH)? (CO2,K2) | 1 |
| | a) $V_{IH} - V_{IL}$ | |
| | b) $V_{OH} - V_{IH}$ | |
| | c) $V_{IH} - V_{OH}$ | |
| | d) $V_{OH} - V_{OL}$ | |
| 1-d. | What determines the threshold voltage (V_{th}) of a CMOS inverter? (CO2,K2) | 1 |
| | a) Only PMOS width | |
| | b) The ratio of PMOS to NMOS sizing | |
| | c) Supply voltage | |
| | d) Load capacitance | |

- 1-e. Which logic gate combination is used in an AOI (AND-OR-Invert) gate? (CO3,K2) 1
 a) AND followed by OR
 b) OR followed by AND
 c) AND followed by NOR
 d) OR followed by NAND
- 1-f. A full adder circuit can be implemented by combining: (CO3,K5) 1
 a) Two half adders and an OR gate
 b) Two half adders and an AND gate
 c) One half adder and a NOT gate
 d) Three half adders
- 1-g. What is the primary issue caused by charge sharing in dynamic logic circuits? (CO4,K2) 1
 a) Increased power consumption
 b) Logic level degradation leading to incorrect outputs
 c) Faster switching speeds
 d) Improved noise margins
- 1-h. In dynamic CMOS logic, during the precharge phase, the output node is: (CO4,K2) 1
 a) Discharged to ground
 b) Left floating
 c) Charged to VDD
 d) Connected to the input signal
- 1-i. In the ASIC backend design flow, which step follows floor planning? (CO5,K2) 1
 a) Verification
 b) Placement
 c) Testing
 d) Synthesis
- 1-j. Which flash memory type is suitable for high-speed random access? (CO5,K2) 1
 a) EEPROM
 b) NOR Flash
 c) NAND Flash
 d) DRAM
2. Attempt all parts:-
- 2.a. Define latch-up in CMOS technology. (CO1,K2) 2
- 2.b. What is CMOS inverter, draw its truth table? (CO2,K2) 2
- 2.c. Differentiate between a latch and a flip-flop. (CO3,K2) 2
- 2.d. Define Domino logic in CMOS circuits. (CO4,K2) 2
- 2.e. What is the main function of a refresh operation in DRAM? (CO5,K2) 2

SECTION – B

30

3. Answer any five of the following-

- 3-a. Explain the major steps in CMOS fabrication? (CO1,K2) 6
- 3-b. What is Gradual channel approximation? Derive the basic current equations for MOS device design. (CO1,K5) 6
- 3-c. What is the significance of device sizing in CMOS inverter design? (CO2,K2) 6
- 3-d. Explain the concept of noise margins in CMOS inverters and how they are calculated. (CO2,K2) 6

| | | |
|--------------------|--|-----------|
| 3-e. | Explain the five regions of operation of a CMOS inverter with the help of VTC curve. (CO3,K2) | 6 |
| 3-f. | Describe the charge sharing problem in dynamic logic circuits and its impact. (CO4,K2) | 6 |
| 3-g. | What is flash memory? Write its applications and advantages. (CO5,K2) | 6 |
| SECTION – C | | 50 |
| 4. | Answer any <u>one</u> of the following- | |
| 4-a. | Describe the VLSI design flow in detail with a diagram. (CO1,K2) | 10 |
| 4-b. | Discuss short channel effects in MOSFETs and their impact on device performance. (CO1,K2) | 10 |
| 5. | Answer any <u>one</u> of the following- | |
| 5-a. | Discuss the types of power dissipation in a CMOS inverter and strategies to minimize them. (CO2,K2) | 10 |
| 5-b. | Consider a CMOS inverter circuit with the following parameters: $V_{DD} = 3.3V$, $V_{Tn} = 0.6V$, $V_{TP} = -0.7V$, $k_n = 200 \mu A/V^2$, $k_p = 80 \mu A/V^2$. Calculate the noise margins of the circuit. (CO2,K5) | 10 |
| 6. | Answer any <u>one</u> of the following- | |
| 6-a. | Design a CMOS circuit for a 2-to-1 multiplexer and explain its operation. Draw it using Transmission gate. (CO3,K2) | 10 |
| 6-b. | Explain the concept of sequential logic circuits and how they differ from combinational logic circuits. Draw NAND, XOR and NOR gates using Pass transistor logic(PTL). (CO3,K2) | 10 |
| 7. | Answer any <u>one</u> of the following- | |
| 7-a. | Discuss the operation of a dynamic CMOS logic gate, explaining the precharge and evaluation phases. (CO4,K2) | 10 |
| 7-b. | Design a dynamic CMOS logic circuit for a 4-input NAND gate and explain its operation. (CO4,K2) | 10 |
| 8. | Answer any <u>one</u> of the following- | |
| 8-a. | Discuss the backend VLSI design flow. Highlight the importance of design rule checking (DRC) and layout rules. (CO5,K2) | 10 |
| 8-b. | Describe the operation and internal architecture of an SRAM cell. Discuss leakage mechanisms. (CO5,K2) | 10 |